

PA-100

QUERY CONTROL FORM		RTIS USE ONLY	
Application No. <u>091777, 516</u>	Prepared by <u>JS</u>	Tracking Number <u>5963396</u>	
Examiner-GAU <u>Fournon-2823</u>	Date <u>7/12/04</u>	Week Date <u>6/17/04</u>	
	No. of queries <u>1</u>	<u>re-USE IFW</u>	

JACKET

- | | | | |
|----------------------|------------------------|--------------------|----------------|
| a. Serial No. | f. Foreign Priority | k. Print Claim(s) | p. PTO-1449 |
| b. Applicant(s) | g. Disclaimer | l. Print Fig. | q. PTOL-85b |
| c. Continuing Data | h. Microfiche Appendix | m. Searched Column | r. Abstract |
| d. PCT | i. Title | n. PTO-270/328 | s. Sheets/Figs |
| e. Domestic Priority | j. Claims Allowed | o. PTO-892 | t. Other |

SPECIFICATION

- a. Page Missing
- b. Text Continuity
- c. Holes through Data
- d. Other Missing Text
- e. Illegible Text
- f. Duplicate Text
- g. Brief Description
- h. Sequence Listing
- i. Appendix
- j. Amendments
- k. Other

CLAIMS

- a. Claim(s) Missing
- b. Improper Dependency
- c. Duplicate Numbers
- d. Incorrect Numbering
- e. Index Disagrees
- f. Punctuation
- g. Amendments
- h. Bracketing
- i. Missing Text
- j. Duplicate Text
- k. Other

MESSAGE

PTO-1449: Please either initial or Libe through citations. 1 copy provided for reference.

Thank you
initials JS

RESPONSE

initials



INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number (Optional)

BREV 12370 CON3

Application Number

09/777,516

Applicant(s)

ASPAR et al.

Filing Date

February 6, 2001

Group Art Unit

2823

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

"Hydrogen-Related Complexes as the Stressing Species in High-Fluence, Hydrogen-Implanted, Single-Crystal Silicon" Cerofolini et al., *Physical Review B*, Volume 46, Number 4, 1992, pgs. 2061-2070

"Crystallographic Nature and Formation Mechanisms of Highly Irregular Structure in Implanted and Annealed Si Layers" Komarov et al., *Radiation Effects*, Volume 42, 1979, pgs. 169-178

"Observation of Blistering and Amorphization on Germanium Surface After 450 keV Ar+ION Bombardment" Kamada et al., *Radiation Effects*, Volume 28, 1976, pgs. 43-48

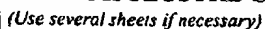
"Orientation Dependence of Flaking of Ion Irradiated Aluminum Single Crystals" Ono et al., *Japanese Journal of Applied Physics*, Volume 25, No. 10, 1986, pgs. 1475-1480

"High Fluence Retention of Noble Gases Implanted in Silicon" Wittmaack et al., *Radiation Effects*, Volume 39, 1978, pgs. 81-95

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



09/777,516

Applicant(s)

ASPAR et al.**Filing Date**

February 6, 2001

Group Art Unit

2823

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

"Applications of Ion Beams to Materials, 1975" Carter et al., Inst. Phys. Conf. Ser. No. 28, Chapter 1, 1976, pgs. 30-36

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.